

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10576220	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	MARCOS BATISTA	2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	466	2/14/2008	mb
455	95	2/14/2008	mb

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Consulted with Steve D'Agosta	2/19/2008	mb
Consulted with TA - Yogesh Aggarwal	2/14/2008	mb
Consulted with Lun-YI Lao	2/19/2008	mb
East Search	2/14/2008	mb
Inventor's Name Seach	2/14/2008	mb
East Search	12/5/2008	mb
Consulted with Rafael Perez Gutierrez	12/4/2008	mb

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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